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Advances in Atomic Force Microscopy for Probing Polymer Structure and Properties

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ABSTRACT: Over the past 30 years, atomic force microscopy (AFM) has played an important role in elucidating the structure and properties of polymer surfaces. AFM-based techniques have enabled the quantitative determination of the physicochemical properties of polymer surfaces with high spatial resolution and under a wide variety of conditions. Coupled with the improvements in spatial and temporal resolution, multiparametric and multifunctional characterization has revealed the delicate interplay between structure, dynamics, and properties at the surfaces of complex systems. Here we summarize some of the significant advances that have



been made in synthetic polymeric materials, most in the past 10 years, where AFM has been crucial, and we provide our perspective on where AFM will be insightful in future and instrumental in advancing emerging areas.

INTRODUCTION

Atomic force microscopy (AFM), since its invention in 1986,¹ has emerged as the dominant tool for imaging the surface topography and quantitatively measuring/mapping the physicochemical properties of a wide range of materials.²⁻⁴ Unlike most imaging techniques that rely on the interaction of photons or electrons with matter, AFM scans a sharp tip attached to the end of a force-sensing cantilever over the surface, measuring the spatial variations of the interactions between the tip and the surface, providing a nanometer-scale (and in some cases atomic-scale) 2D mapping of the mechanical, electrical, magnetic, or topographical properties of the surface.¹⁻⁵ The operation conditions of the AFM are flexible, from vacuum to air to liquid media at reduced or elevated temperatures. The AFM tip can also be used for nanomanipulation and nanofabrication.⁶ The multiparametric and multifunctional characterization, high spatial resolution, and the wide range of operational conditions have made AFM an exceptionally versatile tool that has given rise to numerous discoveries and technologies and opened new opportunities in physics, chemistry, materials, and biology.7

Polymeric materials exhibit spatial and temporal heterogeneities in their properties and, for multicomponent systems, chemical composition that fluctuate about an average value. With the rapid development of advanced polymerization techniques,^{9–11} polymer morphologies are becoming increasingly more complex. Both the applications and developments pose challenges regarding their micro- and nanoscale structure and properties and how they are coupled and finally lead to the emergent bulk properties that determine their ultimate applications. Consequently, imaging polymeric materials with nanoscale resolution and characterizing the surface morphology and topography, while simultaneously measuring and mapping properties, like the storage and loss modulus, provides a unique means of linking structure to properties, deciphering their relationship, and opening pathways for the development of more advanced materials.

Various microscopy techniques, including AFM, optical microscopy (OM), scanning electron microscopy (SEM), transmission electron microscopy (TEM), transmission electron microtomography (TEMT), laser scanning confocal microscopy (LSCM), and X-ray tomography, have been widely used to study the morphologies of polymeric materials. Among these, generally speaking, only AFM can measure a range of properties of polymeric materials, in addition to providing an image. New imaging modes, such as high-speed (HS) scanning¹² infrared spectroscopy,^{13,14} and multifrequency imaging,⁵ have emerged, significantly expanding the spatial and temporal resolution and capabilities of AFM. High spatial and temporal resolution over large areas allows two- or threedimensional mapping of the surface topography and the variation in properties with sub-nanometer lateral and sub-tenth nanometer height resolution. HS-AFM can record images at a rate of \sim 33 frames/s¹⁵ over areas having dimensions from tens of nm to ~100 μ m. Operating conditions can be varied from vacuum to air to liquid media over temperature ranges from

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subambient to elevated temperatures. Multiparametric images of the structure as well as mechanical (such as adhesion, elasticity, and dissipation), electrical, magnetic, and thermal properties can be measured at the speed of conventional topographic imaging. Nondestructive, time-resolved real-space imaging of dynamics and dynamic processes over length scales from the nanometer to many hundreds of micrometers are readily accessible.

Among a wide variety of AFM modes, amplitude-modulation AFM (usually known as tapping mode AFM), force modes (e.g., single-molecule force spectroscopy, nanoindentation, and AFM nanomechanical mapping), electrical modes (e.g., conductive AFM, photoconductive AFM, and Kelvin probe force microscopy) are commonly used to probe polymeric materials. Moreover, the never-ending developments in the modes of operation strengthen AFM continuously, making it an important, if not indispensible, tool for the characterization of polymeric materials. There have been many reviews and treatises on these different methods^{2-4,16-20} and many reviews and books that describe the use of AFM to characterize soft materials;^{3,4,21} most though focus on biological systems.^{8,22,23}

For all AFM modes, a thorough and fundamental understanding of the tip-sample interaction is needed to obtain high-precision images and reliable data. Even for topography imaging, one must understand that AFM is not a camera or a simple profilometer. For example, the most commonly used tapping mode has two tip-sample interaction regimes: attractive and repulsive.^{24,25} The attractive interaction regime allows imaging of the basic morphologies of the sample. More importantly, this regime is able to resolve the detailed structure with high resolution. Imaging in the repulsive interaction regime is associated with the irreversible deformation of a compliant sample, which will lead to a significant loss in resolution and contrast. The crossover between attractive and repulsive regimes will cause changes in height and phase contrast, sometimes appearing as artifacts, and can be related to the particular tip-sample interactions dominating in different set point regimes.²⁶ Here, it also indicates the "height" images obtained in both regimes, particularly in repulsive regimes, do not necessarily reflect the "real" surface topography of the compliant sample because of sample deformation.^{26,27} On the other hand, quantitative nanomechanical mapping has been widely used to measure the nanoscale mechanical properties of polymer materials, but we are still challenged to obtain more than relative values. The factors that affect the accurate measurements of the mechanical properties include not only the commonly stated caveats about unknown tip geometry, errors in instrument calibration (e.g., the cantilever spring constant), or the presence of extrinsic mechanical heterogeneities (e.g., the rigid substrate effect) but also, more importantly, the physical justifications of contact mechanics models on complex polymeric materials.^{28–32} Therefore, developing an understanding of the tip-sample interaction and modeling are always essential to achieve and interpret highquality AFM data (e.g., images, force-distance curves, etc.) and to extract mechanical, electrical, and magnetic properties accurately.

With the rapid development of various AFM techniques, it has now become a routine and, in some cases, an indispensable tool for unravelling the structural and properties of polymers. This is a very broad topic, and as such, we refrain from discussing the wealth of AFM instruments and developments and the basic principles of imaging and measurements in detail here, as they are described in detail in the references cited (e.g., refs 3, 4, 8, and 20). Here, we summarize some of the significant advances that have been made in synthetic polymers, most in the past 10 years, where the advances in AFM played a critical role, and provide some glimpse into future and emerging areas.

STRUCTURE BY AFM: FROM SURFACE MORPHOLOGY TO DYNAMICS

Tapping mode is currently the most commonly used AFM mode for probing polymeric structures. In this mode, the height image depicts the topography, while the phase image, a measure of the energy dissipation during the tip–sample interactions,^{33–36} contains information on the elastic, viscoelastic, and adhesive properties of the sample and topography. Tapping mode AFM has been the mainstay for imaging surface topography, characterizing lateral variation in composition, and lateral heterogeneities in dynamics for a wide range of polymers, from glasses to semicrystalline to block copolymers, rubbers, gels, polymer fibers, polymer blends, and polymer composites.^{3,4,37}

Surface Mobility and Heterogeneity in Glassy Polymer Thin Films. Thin polymer films have striking dynamic properties that differ from their bulk counterparts and, therefore, have practical implications for thin film coatings, lubrication, adhesion, and friction.³⁸ There have been substantial efforts to determine the glass transition and dynamics in films, less than ~100 nm in thickness, using, for example, ellipsometry,³⁹ dielectric spectroscopy,⁴⁰ and X-ray photon correlation spectroscopy (XPCS).⁴¹ Advances in AFM have afforded unprecedented spatial resolution, both parallel to and normal to the film surface, in characterizing the surface topography and viscoelastic properties, providing a direct measure of surface mobility.^{42–49}

A fundamental question with thin polymer films is whether there is a reduction in glass transition temperature T_{g} at the surface and/or if there is a liquid-like layer at the surface. Initial AFM force modulation and lateral force microscopy measurements indicated that the surface mobility of polystyrene (PS) films (200 nm thick) supported on a substrate was higher than that in the bulk, suggesting a reduced T_g at the surface.^{42,50,51} An increase in the surface mobility can be explained by an excess free volume arising from chain end localization at the surface, $^{42,50-52}$ a reduced cooperativity of segmental motions due to the interface with air or vacuum, $^{42,50-53}$ or a looser entanglement of surface chains. 54,55 By capturing very small changes in the surface topography of thin PS films with thermal annealing and analysis of the resultant power spectral density (PSD) data, recent AFM measurements suggested a lower viscosity of surface layer in comparison to the bulk.^{46,56} AFM measurements of the surface relaxation using nanoholes (shown in Figure $(1a-c)^{44}$ or embedded nanospheres^{45,57,58} at the surface of glassy films indicated that the surface relaxed much more rapidly than the bulk and that the surface relaxation had a weaker temperature dependence in comparison to the bulk. Both the reduction of viscosity and the "two-step" embedding process can be explained by a two-layer model, where there is a thin mobile layer with a thickness of a few nanometers. $^{\rm 46,57}$ The relaxation of artificially made steps in PS was measured above and below T_g by AFM, as shown in Figure 1d-g. The planarization of the film surface above T_g was explained by a flow of the entire film, while below T_g only the thin layer near the free surface could flow.⁴⁸ Again, these results are



Figure 1. Schematic diagram of the evolution of nanoholes (a–c) and artificially made steps and flow regions (d–f). (a) The height profile of the sample with a nanohole just prepared. The evolution of the depth of the nanohole after annealing times of (b) t_1 and (c) t_2 ($t_1 < t_2$) at a temperature below T_g of the bulk. The depth of the nanohole decreased with the annealing time owing to the surface relaxation. (d) As-prepared sample at room temperature. (e) The evolution of the total height profile h(x,t) through flow localized in a small region near the free surface, corresponding to the flow mechanism at below T_g , and (f) the evolution of the h(x,t) through whole-film flow, corresponding to the flow mechanism at above T_g . The flow region is indicated in blue. (g) Temperature dependence of the surface mobility ($H^3/(3\eta)$). Reproduced with permission from ref 48. Copyright 2014 AAAS.

qualitatively consistent with enhanced mobility at the free surface of polymer thin films. AFM measurements on the relaxation of thin films showed that substrate interactions can also influence the surface mobility.^{58,59} Contrary to these observations, however, shear-modulated AFM measurements of surface mobility (at 1400 Hz) of PS thin films were found to be independent of film thickness (17–500 nm), strength of substrate interactions, or even the presence of substrate.⁶⁰ This observation may be related to the temperature dependence of surface mobility, where enhancements may be apparent near and below the bulk T_g and, thus, are observable only on very long time scales or at very low frequencies. Measurements performed at higher frequencies, such as those described above, may not be able to discern distinct surface and bulk relaxation processes.³⁸

Thermally driven collective dynamics are important for many macroscopic properties of polymers.^{61–64} However, our understanding of these dynamics, which are cooperative and heterogeneous, remains limited.^{65,66} AFM measurements on the dielectric properties of poly(vinyl acetate) (PVAc) revealed a molecular cooperativity that took the form of transient molecular clusters and nonexponential kinetics near the glass transition.⁶⁷ The wide distribution of relaxation times and the strongly nonexponential behavior, which correlates with a broad distribution of spatial fluctuations or structural heterogeneities near T_{g} will be frozen-in at T_{g} and retained in the glassy state. High-resolution AFM⁴⁷ and nanomechanical mapping⁶⁸ on the surface mechanical properties of PS thin films at room temperature clearly demonstrated nanoscale viscoelastic heterogeneities (shown in Figure 2), 2-3 nm in size, consistent with the size of cooperatively rearranging regions (CRRs) proposed by Adam and Gibbs⁶⁹ and as determined by differential scanning calorimetry,⁷⁰ and with a variation of 57%.47,71 The broadly distributed viscoelastic heterogeneities observed in the energy dissipation map suggest there is a wide distribution of energy barriers for configurational rearrangements and structural relaxations at the glass transition. This corresponds to a very broad range of relaxation times and strongly nonexponential behavior as seen in mechanical or dielectric relaxation spectra.⁴⁷ The AFM results provide direct experimental evidence for the nanoscale heterogeneities in



Figure 2. Tapping mode phase image of PS film with \sim 200 nm thickness. The observed heterogeneity was identified to arise from the inhomogeneous distribution of viscoelastic property. Reproduced with permission from ref 47. Copyright 2012 American Institute of Physics.

glassy polymers and provide insights for understanding the origins of the glass transition.

Polymer Crystallization. Polymer crystallization is one of the most important topics in polymer science. However, despite more than 60 years of intense study, the way in which polymers crystallize and the fundamental processes, such as the formation of initial nuclei and the growth kinetics resulting in folded intermediate metastable states, which result in their highly complex hierarchical structures, are far from being fully understood.⁷² When coupled with a hot stage, AFM is a unique tool for the *in situ* real-time investigation of crystal growth, melting, and reordering process⁷³⁻⁷⁶ at a lamellar and even molecular scale and has provided new insights that could not straightforwardly be obtained with other methods. We focus on the initial development of lamellae and subsequent growth and high-resolution imaging of the crystals. Recent reviews and books^{72,77,78} have dealt with many other topics, including oriented crystallization, effects of confinement, the influence of the substrate on crystallization, and the nucleation process.

In situ real-time AFM studies have provided truly unique insights into the growth of lamellae. Studies on melt crystallization of poly(ϵ -caprolactone) (PCL)⁷⁹ and polypropylene (PP)⁸⁰ indicate that spiral growths generate additional



Figure 3. Torsional-tapping AFM images of the oriented "shish-kebab" crystallization of polyethylene. (a) The amplitude image (grayscale 17 mV) clearly visualized molecular steps from which the stems' orientation could be inferred. (Inset) Distribution of widths of lamellae measured along the stem direction. (b) Details from phase images showing a first-neighbor fold, marked by an arrow, and (c) a second-neighbor fold, with arrows marking the two stems. The grayscales represent a phase lag of (b) 7.7° and (c) 9.2°. Reproduced with permission from ref 98.

lamellar layers at low undercoolings. For poly(bisphenol A octane ether) (PBA-C8) an induced nucleation and subsequent branching was found.⁸¹ The growth tip of PBA-C8 was observed to be softer than the rest of the crystal,⁸² indicating there may exist intermediate degrees of order that are metastable. Lamellae crystallized from the melt showed a nodular texture,^{83,84} suggesting a substructure forms at the growth front of the lamellae, in keeping with the arguments made by Strobl.^{85–87} The crystallization rate, as evidenced by

the work on individual lamellae and lamellar aggregates, varies from crystal to crystal and for each crystal with time. 72,74

For spherulite growth, a depletion zone at the front of a growing spherulite was observed.^{74,75} Initial crystal growth is followed by a protracted period of a backfilling growth and possibly crystal reorganization.⁷² In situ observations showed lamellae twisting to produce banded spherulites where the twisting was a continuous over a substantial fraction of the rotation.⁸⁸ This observation is consistent with X-ray studies⁸⁹ and provides evidence for models on the long distance selforganization of the lamellae.^{90,91} Screw dislocation branches⁷⁶ and other branching mechanisms⁸² were directly visualized. Based on these studies, the formation of a screw dislocation from a defect or fluctuation at the edge of a growing lamella was argued to be the main source of branching in polymers.⁷² Ex situ AFM observations of polyethylene (PE) crystal growth suggested an instability-driven branching mechanisms, arising from a self-induced pressure gradient due to the difference in densities of the crystalline and amorphous phases.^{92,93}

While there are numerous models to describe crystallization, crystallization was not understood on a molecular level. Recently, direct imaging with submolecular resolution, i.e., high-resolution imaging of a two-dimensional (2D) crystal prepared by very slow compression of an isotactic poly(methyl methacrylate) (i-PMMA) Langmuir film has been available.94 The AFM images clearly showed the folding and tie-chains and provided a remarkable snapshot of the arrangement of chains within a crystal.⁹⁴ The crystalline nuclei preferentially form at the end of the chains, and the size of the nuclei was found to be independent of the chain length (molecular weight). At extremely slow compression rates, crystallization was promoted, leading to the crystallization of the entire chain.⁹⁵ The melting behavior of the 2D i-PMMA crystals was also observed in situ at high temperatures with molecular resolution.⁹⁶ The $T_{\rm m}$ of the 2D crystals was depressed significantly, by up to 90 °C, and showed a strong dependence on the molecular weight and nature of the substrate. The large depressions in $T_{\rm m}$ of the 2D crystals could not be explained by a simple modified Thompson-Gibbs equation, creating a theoretical challenge of the age-old problem. The molecular scale observation of 2D



Figure 4. (a, b) Phase images of thin SBS films after annealing in chloroform vapor. Bright (dark) corresponds to PS (PB) microdomains. Contour lines from the corresponding height images are superimposed. (c) Schematic height profile of (a) and (b). (d) Simulated morphology of a BCP film in one large simulation box with increasing film thickness (from left to right). Reproduced with permission from ref 105. Copyright 2002 American Physical Society.

crystals has provided new insights into the polymer crystallization and has presented new challenges.

Direct imaging of chains within a three-dimensional semicrystalline material has been done (Figure 3).^{97,98} Torsional tapping mode AFM imaging of PE, with a 0.37 nm resolution, showed individual chains in the crystalline lattice in air under ambient conditions.⁹⁷ Loose molecular loops at the crystal–amorphous interface and the existence of a tight adjacent fold within this interfacial region were observed.⁹⁷ Images of the adjacent re-entry or random switchboard models.^{99,100} Results from such studies can be directly compared to polymer crystallization theories and molecular simulations, addressing very detailed issues, like the length of stem-to-stem overhang, as shown in Figure 3a.⁹⁸

High-resolution AFM imaging has provided insight into almost every aspect of polymer science and has mapped nanoscale mechanical heterogeneities in glassy polymers⁴⁷ and has been used to characterize phase separation in polymerbased bulk heterojunction (BHJ) organic photovoltaics (OPV).¹⁰¹ Because of structural similarities and low imaging contrast between polymer donors and fullerene acceptors, visualizing structure can be difficult.¹⁰² High-resolution AFM imaging of PTB7/PCBM active layers showed the free surface was enriched with polymer crystals having a "face-on" orientation and an average spacing of ~1.9 nm, and the morphology at the anode interface was markedly different.¹⁰¹

Block Copolymer Assembly. AFM has been extensively used to study block copolymer (BCP) self-assembly,¹⁰³⁻¹⁰ which has recently attracted significant interest from both industry and academia, since the resultant bulk and thin film morphologies offer ideal platforms for the generation of nanoscopically ordered patterns for a range of promising applications.^{106–109} Therefore, an in-depth understanding of these ordered nanostructures with material characteristics and film preparation conditions is essential to further tailor the synthesis of BCPs and for the fabrication of nanopatterns or arrays (Figure 4). In most cases, AFM is combined with electron microscopies or X-ray-based scattering methods to reveal the effects of composition, molecular weight, interaction parameter, interfacial interactions, film thickness, annealing, crystallization, additives, and chain rigidity on the assembly process and the resultant size, shape, and orientation of these nanoscopic structures.^{107,109} Correct assignment of the observed surface pattern to a particular morphology is important for the interpretation of the morphological behavior in thin films. Beyond routine applications, however, advances in AFM make it ideal for studying structural defects and dynamics, self-assembly process, where the aggregates are swollen or filled with solvent (such as micelles or vesicles), and changes of the shape due to deposition on the solid surface and drying.

Structural defects in BCP thin films are common and are known to compromise the long-range lateral order that limit the technological performance of BCPs.^{107,110–113} AFM studies on BCP thin films have identified classical defects (i.e., disclinations and dislocations) as well as grain boundary defect configurations.^{110,112–115} It was found that the motion of lateral defects in cylinder-forming BCPs was diffusion controlled.¹¹⁴ The minimum feature spacing accessible in thin films is limited by thermal defect generation, not by the bulk order–disorder temperature (ODT).¹¹⁶ Such defect densities and the ODT are highly sensitive to variations as small as 2 nm in the microdomain spacing.¹¹⁶ The large shift of monolayer and bilayer ODT caused by variations of the monolayer domain spacing can be explained by the energetic cost of defect production in terms of the domain spacing, interaction parameter, and BCP composition.¹¹⁶ Early works using timeresolved AFM identified relinking, joining, and clustering as basic processes of structural rearrangements.¹¹² When applying an electric field to ABC BCP thin films, AFM showed two distinct defect types that govern the orientation mechanism.¹¹⁷ Moreover, in situ imaging of the dynamics and defect annihilation of polystyrene-b-polybutadiene-b-polystyrene (SBS) during solvent annealing showed a low interfacial energy difference between the cylinder and perforated lamella phases that may account for the energetically favorable path way of structural rearrangements by temporal phase transitions,^{118,119} which was also observed by in situ AFM imaging of SB diblock copolymers under thermal annealing.¹¹¹ This structural rearrangement consists of several elementary dynamic processes, such as short-term interfacial undulations, fast repetitive transitions between distinct defect configurations,¹²⁰ and collective/coordinated movement of annihilating defects,^{114,120} as revealed by high-speed AFM scanning. The fast dynamics of individual defects and their annihilation in thin films of a cylinder-forming BCPs¹²¹ are illustrated in Figure 5.

BCP micelles, vesicles, and other aggregate structures have emerged as versatile drug delivery systems, nanoreactors, or as templates for nanoparticle synthesis.^{122,123} Besides scatteringbased methods¹²⁴ and wet scanning and cryogenic TEM,¹²⁵ AFM has been used to provide *in situ* information about the growth of these aggregate structures in solution by tracking the shape of self-assembled aggregates.^{126–128} Varying the architecture of the BCPs, the nature of the solution,^{126,127} and the underlying surface^{126,128} have opened numerous routes to control surface topology, domain size, and wall thickness of the aggregate structures. For example, the poly(2-(dimethylamino)ethyl methacrylate)-*b*-poly(methyl methacrylate) (DMA-MMA) adsorbed on mica showed surface micelles at low pH and regions of close-packed structure at higher pH, indicating the importance of pH in the resultant morphology of



Figure 5. (a) AFM phase images visualized climb motion of two dislocations of opposite Burgers vectors with annealing time. The two dislocation cores were indicated by the arrows. (b) The plot of square of the distance between the two dislocation cores versus corresponding time. Reproduced with permission from ref 121.



Figure 6. (a) AFM height image of polystyrene-*b*-poly(methyl methacrylate) (PS-*b*-PMMA). The width scale of (a) is 500 nm. Reproduced with permission from ref 169. (b) AFM image of poly(*n*-butyl acrylate) (PBA) brushes made from poly(alkyl acrylate) and poly(alkyl methacrylate) backbones (white arrow pointing to branch junctions). Reproduced with permission from ref 174. (c) AFM height images of the PBA bottlebrushes with the same backbone but different of the degree of polymerization of side chains on a mica substrate. Large images: LB monolayers. Insets: single molecules prepared by spin-casting. Reproduced with permission from ref 170. Copyright 2016 the Nature Publishing Group.

the polyelectrolyte diblock.^{126,128} For a poly(oyxethylene)-*b*-poly(oyypropylene) diblock, a more highly ordered structure was found on a hydrophobic silica substrate,¹²⁸ demonstrating the importance of the chemical nature of the surface on the resultant morphology of the amphiphilic diblock.

Polymer Subsurface Structure. The surface and bulk morphologies of polymeric systems are often different. Reconstruction of three-dimensional (3D) structures is becoming increasingly important.¹²⁹ TEMT has been widely used to this end.¹³⁰ AFM is a surface technique, but if sectioning or etching is used in tandem with AFM, subsurface structures can be determined. This was demonstrated in the elucidation of the bicontinuous interpenetrating network in PTB7-based bulk heterojunction active layers.^{101,131} Nanotomography¹³² has also been developed for the *in situ* observation of crystal growth of elastomeric polypropylene, where the origins of a lamellar branch was found to originate in

a screw dislocation.¹³³ This layer-by-layer imaging technique was further developed to operate under various conditions and AFM modes^{134–136} and found use in the solvent vapor annealing of BCPs under electric fields¹³⁷ and visualization of conductive 3D networks of polymer/MWCNT nanocomposites using c-AFM.¹³⁵

The methods described above involve destructive sectioning or etching procedures. Nondestructive subsurface structure imaging by AFM is under very active development with some progress being made using ultrasonic wave or energy dissipation. These have been demonstrated in several polymeric and cellular systems.^{138–141} For example, the reconstruction of the subsurface structure of supramolecular aggregates of oligothiophenes yielded a 3D picture consisting of 15 nm wide fibrils with a rigid core and a soft shell.¹⁴⁰ In the P3HT system, the crystalline regions and crystalline fibers were found to be covered by an \sim 7 nm amorphous layer after solvent



Figure 7. (a) Scheme of SMFS experiment. Reproduced with permission from ref 182. Copyright 2006 Elsevier. (b) A force plateau at \sim 13 pN is observed in the extension–retraction curve of an individual, collapsed PS chain in water. Black curve shows extension (pulling) of a single molecule and gray curve shows retraction (relaxation) process. Drawings along the curve illustrate the chain configurations of the extension of a single polymer chain in poor solvent. Reproduced with permission from ref 190. (c) Scheme of the force-induced rotation of carbon–carbon double bonds. Reproduced with permission from ref 200. (d) Scheme of extracting a single poly(ethylene oxide) chain from a single crystal by SMFS and corresponding force–extension curves. Reproduced with permission from ref 211.

casting that decreased to 5 nm after thermal annealing.¹³⁹ The presence of the amorphous surface layer has important consequences in the charge-transfer process. For polymer nanocomposites, related techniques were used to probe 50 nm gold particles buried in polymer matrix under ~1 μ m.¹⁴² The nondestructive subsurface imaging was also operated under an applied electric field, where the dispersion and orientation of CNTs in polymers were determined with nanometer-scale resolution.^{143,144} These results provided in-depth morphological information and, hence, are expected to facilitate the analysis and preparation of polymer nanocomposites in the future.

Polymer Molecules Engineered Surface. AFM has played a key role in understanding surface modification by tethering various polymer molecules using grafting, selfassembly, or adsorption onto substrates.¹⁴⁵ The morphology of the engineered surfaces is critical in defining the properties. AFM topography imaging of such surface has quantified the morphologies and morphological transitions as functions of grafting density¹⁴⁶ and thickness of grafted layers.^{147,148} The thickness of the engineered layers especially for polymer brush modified surface is often used to quantify structural changes as a function of solvents, pH, temperature, and ionic strength. AFM has subangstrom height resolution and, therefore, can measure the layer thickness fast and accurately by cross-section analysis of the polymer covered and uncovered regions.¹⁴⁹ Recently, AFM force-distance curve measurements were used to determine the layer thickness.¹⁵⁰⁻¹⁵² The applied loading force should must be considered when using AFM to measure the layer thickness, especially with compliant polymer layers, since the deformation of the polymers will cause errors in the measured height values.^{153,154} For polymer brush modified surfaces, average molecular weights of the brush were determined by measuring the heights of the brushes in a good solvent in comparison to the known monomer length.¹⁵⁵

Stimuli-Responsive Behavior. AFM can be used to monitor *in situ* the changes in properties (such as adhesion,

wetting, mechanical performance, and friction) of stimuliresponsive polymers in response to external stimuli, such as pH,^{156,157} temperature,^{155,158} ionic strength,¹⁵⁹ light,¹⁶⁰ etc. Here, well-known responsive poly(*N*-isopropylacrylamide) (PNIPAM)-based polymers¹⁶¹ show a reversible coil to globule transition at the so-called lower critical solution temperature (LCST). Above the LCST, in the collapsed state, hydrophobic polymeric aggregates are seen at the polymer surface, causing an abrupt change in the average film thickness and a dramatic increase in the roughness.¹⁵⁵ This transition was also observed for end-grafted polymer chains that had been grown from surface-immobilized monomers.¹⁶² The transition dynamics under external stimuli can be easily measured by simply tracking the height change. High-resolution AFM measurements of a poly(methacrylic acid) brush in response to pH changes showed swelling and collapse transitions that occur on the subsecond time frame.¹⁵⁷ During the transition, molecular chains rearranged to another equilibrium structure in response to the external stimulus, and when compared to the measured mechanical properties, the structure-mechanical property relationship was directly determined.¹⁶³ Such information provided a better understanding of the structural complexity and responsive behavior of these advanced stimuli-responsive polymer materials under external stimuli.

Self-healing polymers represent one of the forefronts in materials chemistry and engineering.¹⁶⁴ AFM can be employed to image the healing process of this stimuli-responsive polymers. AFM imaging of the morphology changes as a function of temperature or time showed the healing process, uncovering the importance of polymer mobility in the healing. These *in situ* AFM observations provided fundamental insights into the healing of the domain morphology at the nanoscale.^{165,166}

Polymer Chain Conformation. *In situ* visualization of single polymer chains and their motions have long been a challenge in polymer science.^{167,168} Until recently, AFM imaging of a polystyrene-*b*-poly(methyl methacrylate) (PS-*b*-

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PMMA) BCP LB film first visualized random coil conformations of a single synthetic polymer chain frozen on a substrate (Figure 6a).¹⁶⁹ Shortly thereafter, various structures such as polymer brushes,¹⁷⁰ dendron polymers,¹⁷¹ polyelectrolytes,¹⁷² and star polymers¹⁷³ were observed. In a case study, AFM molecular imaging of branching in linear acrylate-based macromolecules provided direct and quantitative information about branching topology including length and distribution of branches, not accessible by other methods (shown in Figure 6b).¹⁷⁴ This capability was also verified in a study of solventfree, supersoft, and superelastic polymer melts and networks prepared from bottlebrush macromolecules, in which AFM molecular imaging qualitatively corroborated the increase in diameter and rigidity of bottlebrushes with increasing of the degree of polymerization of side chains (Figure 6c-f).¹⁷⁰ Not only the static structure but also the dynamic movements, i.e., the conformational rearrangements, of isolated chains in various environments were visualized. ^{172,173,175,176} Such molecular-level information, including static conformations and dynamics of conformational transitions, has greatly improved our understanding of the physical properties of polymers.

MECHANICAL PROPERTIES BY AFM: FROM MOLECULE SCALE TO MESOSCOPIC SCALE

Polymer materials often exhibit heterogeneities in material characteristics and chemical composition which, as we drive toward ever decreasing feature sizes or thicknesses, understanding the characteristic length scales and dynamics of these heterogeneities becomes increasingly important. AFM serves as a tool to provide such characterization of the surface. Here, we focus on recent progress made with the SMFS and AFM nanomechanical mapping—two typical force measurements and studies of synthetic polymers.

Single-Molecule Force Spectroscopy (SMFS). The principles and use of SMFS can be found elsewhere.¹⁷⁷⁻¹⁸ In a typical experiment, a functionalized AFM tip is brought into contact with the sample surface, where polymer chains have adsorbed. A single molecule can be bound to the tip and the substrate, by physical adsorption, ligand-receptor interaction, or covalent bonding. The force as a function of the distance that the cantilever has traveled vertically is measured as the molecule is stretched and eventually debonds or breaks, as shown in Figure 7a. The resultant force-distance curves provide not only the strength of the binding interaction but also insights into the elastic properties, conformational changes, and the unfolding of stretched polymer chains with piconewton sensitivity and subnanometer accuracy. Shortly after the development of SMFS in a polysaccharides study,¹⁸³ extensive works on inter/intramolecular forces of various polymer systems were investigated.

SMFS studies have shown that at low forces (<100 pN) the mechanical behavior of polymer chains is mainly affected by its entropic elasticity, while at high force region, larger than 300 pN, it is mainly affected by the enthalpic elasticity.¹⁸⁴ The side chain effects on the elasticity of polymer chains showed that for polymers with the same backbone the chains with larger side groups showed higher stiffness.^{185,186} Recent SMFS measurements on polymers with side chains of different lengths and shapes revealed that only long and bulky side chains affected the enthalpic elasticity of the chain.¹⁸⁴ While such studies directly correlate the molecular structure of the polymers to the mechanical properties of a single chain, translating this, in general, to macroscopic properties is still a challenge, though

some success was obtained with a biomimetic designed polymer.¹⁸⁷ Here, the complete, asymmetric potential energy profile of the rupture and refolding of each monomeric module showed a correlation with the bulk mechanical behavior by DMA measurements.

Interactions between the solvent and polymer chains are also critical, as the aggregation state of polymer chains also affects the mechanical behavior of the polymer.^{186,188–192} The formation of hydrogen bonds, the solvent quality, and the size of the solvent molecules, i.e., the excluded volume, will influence the measured elasticity of the single chain.^{188,189,192} By measuring the elasticity in different solvents, information about type and strength of interactions between the polymer and small molecules can be determined. As would be expected, with a polyelectrolyte, the charge density on the chain plays a critical role in its elasticity.¹⁹³ For PS chains, however, the elasticity constant was found to be the same for all different organic solvents investigated, but Kuhn length increased systematically with increasing solvent quality, reflecting the larger extent of swelling of the polymer in good solvents.¹⁹²

Force-induced conformational transitions of single polymer chains can provide fundamental information about internal structure.^{194,195} SMFS measurements of a PS chain in water, for example, showed three regions of the mechanical response corresponding to chain extension (retraction) and a forceinduced globule-coil transition of polymer chains (Figure 7b), ^{196,197} Here, providing definitive proof of theoretical predictions.¹⁹ the hydrophobic PS chains collapsed in water due to nonfavorable interactions with water,¹⁹¹ manifesting a classic collapse mechanism where the hydrophobic domain size dictated the structure and dynamics of water near polymers.¹ Force-induced isomerization of the gem-dibromocyclopropane (gDBC) into 2,3-dibromoalkenes was observed during the stretching of a gDBC-functionalized polybutadiene.¹⁹⁹ The structural rearrangement indicated the localized stress could be relaxed in polymers and polymer networks under load.¹⁹⁹ More recently, force-induced cis-to-trans isomerization of carboncarbon double bonds has been observed in several polymer systems (Figure 7c).^{200,201} These SMFS results indicate unique possibilities to develop advanced force-responsive materials. SMFS measurements on a more complex polymer system forced unfolding of single-chain polymer nanoparticles (SCNPs), provided insights into the interior structure of SCNPs, and by analysis of rupture events observed in the force profiles afforded insights into the assembly mechanism of the SCNPs.²⁰² Force-inducted structural transitions also provided important structural information on cross-linked polysaccharides²⁰³ and disassembling block copolymer and micelles.^{204,2}

SMFS can also provide quantitative information about intra/ intermolecular interactions of polymer molecules^{177,180,206,207} as well as desorption forces of polymer chains from the substrate surface.^{193,208,209} Most SMFS studies on intermolecular interactions have focused on biological samples, since such interactions dictate the self-assembly process and direct the assembly of molecular building blocks into organized supramolecular structures, which is key for biological processes. Nonuniform force plateaus were observed when carboxymethycellulose (CMC) molecules were pulled out of a polymer film into a poor solvent and were described by a geometric model that involves the polymer–polymer and polymer– solvent interactions.²¹⁰ Recent SMFS studies on the pull-out of a single poly(ethylene oxide) (PEO) chain from a single crystal (shown in Figure 7d)²¹¹ clearly demonstrated the adjacent re-



Figure 8. (a) Scheme of SMFS mapping of RAFT-controlled macromolecular growth. (b) Typical force-distance curves of poly(hydroxyethyl methacrylate) (PHEMA) strands that have different chain length. (c) Plot of contour length of the PHEMA chains versus polymerization time. Reproduced with permission from ref 215.

entry of the PEO chains in the single crystal prepared from dilute solution. $^{\rm 212}$

SMFS has also been used to the determine molecular weight, molecular weight distribution, and grafting density^{150,213} of surface-grafted polymers,^{150,213–215} which has been a longstanding challenge.¹⁴⁵ SMFS results for a polycation, poly[2-(dimethylamino)ethyl methacrylate] (PDMAEMA), grafted from a poly(methyl methacrylate) (PMMA) backbone were shown to be consistent with results from gel permeation chromatography.²¹⁴ SMFS mapping on RAFT controlled macromolecular growth on glass surfaces showed the RAFT chain extension linearly with time up to high conversions (Figure 8), providing critical insight into macromolecular growth of the surface-initiated polymerization.²¹⁵

AFM Nanomechanical Mapping (AFM-NMM). AFMbased NMM modes, such as force modulation,²¹⁶ force volume,^{27,217} lateral force microscopy (also known as friction force microscopy),²¹⁸ contact resonance,²¹⁹ peak force tapping,^{220,221} nanoindentation,^{222,223} multifrequency force microscopy,⁵ and also tapping mode phase imaging,²²⁴ provide sample properties while simultaneously imaging the topography. A versatile and widely used approach among these is the force-distance (FD) curve-based imaging where an AFM tip scans over a specified area of the sample surface, and the corresponding applied force versus tip displacement is determined. Using appropriate contact mechanics models, such as the Hertz,²² ³ Johnson–Kendall–Roberts (JKR),² and Derjaguin-Muller-Toropov (DMT) models,²²⁷ the 2D FD images can be translated into an areal mapping of the surface mechanical properties, including the elastic modulus, adhesion, dissipation, and stiffness. By simultaneously providing microstructure and mechanical properties with nanometer resolution and piconewton sensitivity, AFM-NMM has become a routine tool for probing polymer structure and determining local mechanical properties. Several pioneering studies using AFM-NMM on polymers have been published. 3,4,16,19,21,216

The mechanical properties of thin and ultrathin polymer films are of critical importance for many applications, ranging from coatings to organic electronics. AFM-based nanoindentation measurements on thin polymer films supported on a noncompliant substrates showed that the effective out-ofplane modulus increases with decreasing film thickness when it is smaller than a threshold film thickness.^{228–230} This

enhancement of the elastic modulus can be explained by the propagation of the indentation-induced stress field and the interactions between the thin film and the underlying substrate.^{230,231} The indentation-induced stress field propagation was found by measuring the elastic modulus of linear PS (LPS) and star-shaped PS (SPS). This was more evident for SPS than the LPS, indicating a more efficiently "packing" of the SPS, allowing a more efficient stress transfer.²³¹ Interactions between the thin film and the substrate were also found to affect the elastic modulus of the thin films. AFM nanoindentation simulations on the interfacial mechanical properties near attractive interfaces of supported PMMA thin films indicated that there was a gradient of local modulus with larger values near the substrate compared to the bulk, giving rise to interfacial confinement effects.²³² Force volume NMM measurements on rubbery poly(vinyl acetate) (PVAc) thin films further revealed the intermolecular interactions induced by nanoconfinement significantly affected the elastic and viscoelastic responses of polymers.²³³ The above results provided important insights into the origin of the thicknessdependent mechanical properties of thin polymer films.

Characterization of the microstructure and mechanical properties at interfaces in polymer blends and composites has been a long-standing academic and technological challenge, since they dictate the ultimate properties. Studies on polystyrene/poly(n-butyl methacrylate) (PS/PnBMA) blends using AFM-NMM showed a gradual decrease in the Young's modulus from that of PS to that of PnBMA, clearly demarking the interfacial region.²³⁴ AFM-NMM measurements of the reactive compatibilization of polyolefin elastomer (POE)/ polyamide (PA6) blends demonstrated an interfacial reaction induced roughening and simultaneously afforded the strength and width of the interface.²³⁵ The ability to map the spatial distribution of Young's modulus at an interface provides an alternate, efficient means of characterizing interfaces. This, of course, enables the investigation of polymer-polymer interdiffusion (shown in Figure 9);^{221,236} polymer-fullerene nanoparticle interdiffusion;²³⁷ compatibilized polymer blends where increased interfacial interactions of immiscible polymers mediated by an ionic liquid were revealed;²³⁸ fiber reinforced polymer composites;²³⁹ and carbon black reinforced rubber nanocomposites, where the thickness and elastic properties of the bound rubber phase were observed²⁴⁰ and confirmed by

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simulations.²⁴¹ Given the importance of the interface in defining properties of polymer blends and composites, AFM-NMM provides a unique view.

There has been much interest in the deformation mechanism of various polymers since the roles of molecular orientation and deformation-induced structural changes have been found to be of particular importance for the ultimate properties of a polymer. Although X-ray diffraction/scattering was widely used to probe the local molecular structure and structural dynamics of various polymers during deformation, they provide only structural information that is averaged over the area irradiated with the X-ray beam. With AFM real-space imaging, considerable information regarding polymer chain orientation, structural transition and dynamics, and fracture under deformation can be visualized. Such studies, using contact or tapping mode AFM, have been performed on semicrystalline polymers,^{242–244} elastomeric polyolefins,^{245,246} thermoplastic vulcanizates,²⁴⁷ and stretchable electronic devices.²⁴⁸ The realspace features of uniaxially stretched iPP sheets observed with frequency-modulation AFM were successfully compared with the X-ray scattering results obtained by synchrotron X-ray scattering.²⁴⁹ Not only structural information but also the mechanical properties associated with structural developments under deformation are also of interest. Several recent studies using AFM-NMM have been performed on polymer hydrogels,²⁵⁰ semicrystalline polymers,^{251,252} and elastomers.^{253,254} In a case study, AFM-NMM measurements on the structural evolution and mechanical properties of a deformed isoprene rubber (IR) clearly demonstrated a hierarchical nanofibrillar structure, ranging from several to a hundred nanometers in size, comprised of fibers oriented parallel to the stretching direction (Figure 10). The nanofibers, connected by oriented amorphous tie chains, form a network structure that was responsible for significantly enhanced stress, a key factor giving rise to the selfreinforcement of IR.25

Information about the viscoelastic properties at the nanoscale is another essential characteristics of polymeric materials and also an emerging area of AFM investigation. As discussed earlier, viscoelastic measurements using several AFM modes (e.g., force modulation, lateral force microscopy) have shown that there is a surface mobile layer with a reduced T_{σ} in comparison to the bulk. With FD curve measurements, AFM-NMM, by analyzing changes in the pull-off forces in the vicinity of the glass transition, provided a means to determine the T_g of the topmost polymer layer.^{55,255} Not only T_{g} , FD measurements on glass-to-rubber transition of amorphous polymers could be used to estimate the parameters of the Williams-Landel-Ferry equation and the Young's modulus and the yielding force of the polymer in a wide range of temperatures (70 K) and probe rates (6 decades), and the results are in very good agreement with measurements performed with customary techniques, such as broadband spectroscopy and dynamic mechanical analysis (DMA).²⁵⁶ In more recent studies, viscoelastic properties can be mapped into a 2D image with nanometer spatial resolution.²⁵⁷ As a case study, the viscoelastic properties including the storage modulus, loss modulus, and tan δ of styrene–butadiene rubber (SBR), IR, and a SBR/IR 7/3 blend were estimated and visualized from 1 Hz to 20 kHz using a recently developed nanorheology mapping technique.²⁵ These quantities obtained by AFM were in agreement with those measured using bulk DMA. Through this evaluation, nanorheology mapping has been shown to be a highly promising AFM mode for quantitative characterization of



Figure 9. AFM-NMM Young's modulus maps of the miscible poly(vinyl chloride)/poly(caprolactone) sample annealed at 72 $^{\circ}$ C for (a) 5, (b) 20, and (c) 50 min. Reproduced with permission from ref 221.

viscoelastic materials at the nanoscale, and its benefit to the research and development of small-scale compliant materials is expected to be substantial.

In view of the increased importance of tribological properties (friction, lubrication, and wear) of the surfaces and interfaces of polymeric materials in lubrication, M/NEMS (micro/nano electromechanical devices), biomedical implants, and others, a molecular-level understanding of such tribology behavior is of special interest^{259,260} and an increasingly active area of AFM-NMM investigation.^{261–263} Early work on estimation of nanotribological properties by AFM-NMM has been shown for polymer blends,²⁶⁴ thermoplastics,²⁶⁵ and glassy polymers,²¹⁸ but most recent work has been focused on polymer brushes^{266–269} because of their unique properties, such as reversible switching behavior, multivalent functionalization, tunable wettability, and lubrication. In most cases, several FD curve-based AFM-NMM techniques, such as lateral force and chemical force microscopies, are combined to estimate the tribological properties, for example, friction, adhesive, and elastic properties with nanometer resolution and under a wide variety of conditions. AFM-NMM measurements of the nanomechanical and nanotribological properties of polyelectrolyte brushes provided insights into how the Young's modulus and coefficient of friction can be tuned by varying the pH of the surroundings and the degree of physical or chemical cross-linking.²⁶⁷ For polymer brush measurements, it is crucial to use colloidal probes because of their well-defined tip geometry and, therefore, can have a good match between the measured force-distance curves and theoretical models to



Figure 10. AFM-NMM images of stress distribution of isoprene rubber (IR) visualized structural evolution with strain 0% (a), 300% (b), 500% (c), and 600% (d). The strain is applied in the vertical direction of these images. Reproduced with permission from ref 253.

get mechanical properties accurately. This is also true for AFM measurements on mechanical properties of gels, which is increasingly important polymeric materials.

The importance of AFM-NMM was also demonstrated in other polymer systems, such as polymer nanofibers, where, by measuring the nanoscale mechanical properties of single fibers, the packing density and structural heterogeneity could be determined;^{270–273} stimuli-responsive polymers such as PNI-PAM that shows a well-known temperature-induced conformation transition at LCST, where the nanomechanical properties below and above the LCST, as well as on the dry state, were addressed;^{274,275} semicrystalline polymers, in which the crystalline regions covered by a thin amorphous layer, were revealed;^{276,277} and block copolymers, in which various local nanomechanical properties, not only Young's modulus but also adhesion and energy dissipation, were evaluated.^{278–281}

NANOSCALE ELECTRICAL AND ELECTRONIC PROPERTIES BY AFM

Polymer-based solar cells (PSCs) have attracted significant attention from both academia and industry due to their semiconducting properties and potential for low-cost, flexible devices for alternative energy sources.²⁸²⁻²⁸⁴ For PSC devices, donor/acceptor blends absorb photons to generate excitons, which then migrate to the donor/acceptor interfaces where they dissociate into free charge carriers. This process is dependent on nanoscopic details of the morphology, which is dependent on the chemical compositions and processing conditions.^{285,286} Advanced AFM modes including conductive AFM (c-AFM), photoconductive AFM (pc-AFM), and scanning Kelvin probe force microscopy (KPFM) have been used to gain an understanding of the structure-performance relationship for the active layer of PSCs.²⁸⁷⁻²⁹¹ c-AFM, a derivative of AFM contact mode, characterizes the electrical characteristics with a typical spatial resolution of 10-20 nm. In this mode, a dc bias is applied between the conductive tip and sample while the tip scans over the sample surface, and information about the nanoscale topography and current distribution (conductivity) is recorded simultaneously. Studies using c-AFM clearly visualized, as evidenced by current distribution map, the phase-separated donor and acceptor regions and the electron- and hole-transport networks.²⁹²⁻ Heterogeneous conductive regions smaller than 20 nm were detected.²⁹⁷ The thermal annealing induced heterogeneous

conductivity in poly(3-hexylthiophene) (P3HT) thin films^{297,298} increased hole and electron mobilities in P3HT/ [6,6]-phenyl C61-butyric acid methyl ester (PCBM) blends²⁹² and decreased the width of the interface between the donor and acceptor regions.²⁹⁶ The use of solvent additives resulted in a finely phase-separated morphology²⁹⁵ as evidenced by c-AFM. Consequently, the processing conditions that determine the morphology of the active layer could be directly correlated with the PSC performance.

Similar to the force-distance curves, current-voltage (I-V) curves can also be extracted from c-AFM and provide some underlying information on electron conductivity and mobility of the nanostructures, such as the hole mobilities of P3HT in neat P3HT films,^{294,299} in poly(3-alkylthiophene) (P3AT) nanofibers,³⁰⁰ or in P3HT:PCBM blends,²⁹² which could never be determined by macroscopic J-V measurements. It should be noted that there may be a large discrepancy between the charge carrier mobility measured with c-AFM and that measured by a macroscopic planar device^{299,301} due to the geometric differences between the two experiments and the areas over which the different methods average.²⁹⁹ Using a semiempirical equation proposed by Reid et al.,²⁹⁹ however, reliable mobilities can be extracted, allowing the measurement of local mobilities with nanoscale resolution in the heterogeneous films used in light-emitting diodes, transistors, and solar cells.

It is more interesting, however, to obtain information on the photocurrent generation at the nanoscale that can be used to correlate with charge generation, transport, and collection that dominate bulk device performance. pc-AFM, a derivative of c-AFM but with the addition of a diffraction-limited laser source to illuminate the device (Figure 11a), has been used to resolve the complex optoelectronic and morphological phenomena of PSCs with a typical resolution of 10-20 nm.³⁰²⁻³⁰⁹ Photocurrent mapping of a poly[2-methoxy-5-(3',7'-dimethyloctyloxy)-1,4-phenylenevinylene] (MDMO-PPV)/PCBM film gave evidence for two length scales of heterogeneities arising from the solvent casting conditions (shown in Figure 11).³⁰² In P3HT:PCBM films, pc-AFM data showed significant inhomogeneities on the length scale of 100-500 nm, arising from local variations at the surface, not reflecting the bulk organization.³⁰⁴ In a high-performance PTB7:PCBM blend, pc-AFM revealed a bulk heterojunction (BHJ) structure consisting of elongated PCBM-rich and PTB7-rich fiber-like domains, 10-50 nm wide and 200-400 nm long, indicating that the formation of narrow

and elongated domains is desirable for efficient BHJ solar cells.³⁰⁹ Moreover, not only the surface but also the subsurface morphology can be revealed by pc-AFM, with an estimated depth resolution of \sim 20 nm within the P3HT:PCBM film.³⁰⁷

KPFM, a noncontact variant of AFM, can be used to probe local surface potentials (work function) to local morphologies with a resolution better than 10 nm.^{310,311} KPFM is contactless, which is an important when dealing with soft organic thin films. Early studies of MDMO-PPV/PCBM blends using KPFM identified a barrier for electron transmission from the electron-rich PCBM nanoclusters toward the extracting cathode.³¹² In polyfluorene-based photodiodes, KPFM revealed the presence of a capping layer that reduces the efficiency of the photovoltaic device by blocking the transport of photogenerated electrons to the surface.³¹³ With improved resolution down to sub-10 nm, surface morphologies of the interpenetrated networks of P3HT:PCBM blends are clearly evident, and the carrier generation at the donor-acceptor interfaces and their transport through the percolation pathways in the nanometer range have been directly visualized.³¹⁰ KPFM studies on P3HT-b-P3MT and P3HT nanofibers showed that the surface potential, related to the work function of the sample, is very sensitive to the nanostructure morphology resulting from a combined effect of chain-packing disorder, molecular weight, and local environment.^{314,315} The decay of the surface potential into the film was determined on the ~millisecond scale, which suggested an intensity-dependent recombination kinetics that is in quantitative agreement with the carrier recombination kinetics measured in bulk devices.³¹⁶

The combination of AFM-based techniques, such as c-AFM, pc-AFM, and KPFM, provides comprehensive characteristics of the local morphology and the electrical and optoelectronic properties of PSCs, thereby establishing a direct correlation of local heterogeneities within the nanostructure and photocurrent generation in the bulk device.^{287–291} Studies in P3HT/ PCBM blend devices showed that the thermal annealinginduced morphological heterogeneities, as seen in the distribution maps of local current (by c-AFM) and shortcircuit photocurrent (by pc-AFM), may lead to the imperfect internal quantum efficiency of some blends.³⁰³ In a poly(3butylthiophene) (P3BT):PCBM blend device, the direct connections between local nanostructure and overall device performance, as shown in the local current and photocurrent maps, showed that the nanostructure, controlled by using a combination of thermal and solvent annealing, is the single most important variable determining the device performance,³⁰⁵ while in a P3HT nanowire:PCBM blend devices, the results demonstrated the importance of vertical morphology within the active layer on the device performance.³ Copolymer-based devices, in contrast to the physically mixed polymer:fullerene blends, are inherently microphased separated on the tens of nanometers level, underscoring the importance of molecular design and morphological control that determine the nature of the self-assembled nanostructures for developing highly efficient polymer:fullerene PSCs.³⁰⁸ Since c-AFM and pc-AFM are operated in contact mode, c-AFM and pc-AFM still face challenges including scan-induced damage,³⁰⁶ injection/extraction barriers due to the work function of the tip,³¹⁷ and difficulty in making quantitative comparisons with the external quantum efficiency (EQE) of the macroscopic diode.



Figure 11. (a) Schematic of the pc-AFM setup. pc-AFM height image (b) and photocurrent map (c) of a MDMO-PPV:PCBM 20:80 thin film. (d) Local current–applied voltage curves acquired at three locations shown in (b) and (c). Inset: local current–voltage curves without illumination showing much smaller dark currents. Reproduced with permission from ref 302.

PROSPECTS

The past 30 years have seen considerable impact of AFM on our understanding of polymers. With the advances of multiparametric and multifunctional characterization with high resolution and the capacity to operate under various media, AFM is well positioned to tackle the challenges of understanding the structure and properties of increasingly more complex polymers and their composites. In measurement developments, for example, multifrequency AFM is emerging and provides a promising framework to improve compositional sensitivity and spatial and time resolution of materials in their native environment.³¹⁸ In a case study, bimodal AFM (one kind of multifrequency AFM) imaging of metallopolymer-grafted diblock copolymers clearly revealed a lamellar morphology featuring a spherical substructure for the polyvinylferrocene (PVFc) segments inside the polyisoprene lamellae.³¹⁹ The morphological structure of the grafted diblock copolymer measured by bimodal AFM is in excellent agreement with the TEM and SAXS,³¹⁹ indicating the high sensitivity for

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compositional heterogeneities well suited for the highresolution imaging of polymers. Combining AFM with existing techniques, in particular chemistry related characterizing methods, put AFM at an even more advanced level. AFM-IR, combining AFM and infrared spectroscopy, opens a door to nanoscale chemical characterization, where the spatial variation in infrared absorption and reflection with up to a 15 nm resolution is possible.^{14,320,321} This advance paves the way for new insights into the underlying structure beyond phenomenological physical responses (e.g., dissipation and mechanical properties), of a wide range of polymer materials, such as polymer blends, composites, fibers, and thin films for active devices, such as organic photovoltaics. Several recent studies using AFM-IR have shed some light on the structures and compositions with micro- and nanoscale feature sizes, 322-324 which were not been possible by either conventional IR or AFM. The capabilities of AFM-IR, with the addition of some other accessories, such as a polarization control, can be further extended to probe the orientation in anisotropic supramolecular assemblies.³²⁵ The combination of AFM with mass spectrometry (MS) for topographical and chemical imaging of polymer systems has also emerged very recently.³ Moreover, the combination of two or more AFM-based modes to characterize multiple aspects of polymers is another promising way to characterize polymers with exceptional spatial resolution. Such a combination, for example, AFM and scanning electrochemical microscopy (AFM-SCEM), provided spatially correlated electrochemical and nanomechanical information paired with high-resolution topographical data of soft electronic devices.³²⁸ It is evident that such combinations will allow AFM methods to meet the challenges posed by increasing complexity in structure and function of polymer materials.

Despite the wealth of information AFM provides, an important limitation is the relatively slow data acquisition times that lead to difficulty in following many dynamic processes and structural transitions of polymers occurring on the nano- to microseconds time scale. Although recently commercialized high-speed AFM (HS-AFM), which allows images to be collected at video rates, has provided new insights into the nanostructural dynamics and dynamic processes of biological samples,^{15,329} its application to polymeric systems has been limited, since it requires relatively large tip-sample forces to keep constant tip-sample contact. With improved force and drift control systems, HS-AFM would make a considerable impact on our understanding of structural dynamics of polymers, such as polymer crystal growth and BCP assembly. Another unresolved, also the most important, issue for highprecision AFM images and absolute property measurements is developing an understanding of tip-sample interactions and modeling (e.g., contact mechanics modeling, tip shape modeling, etc.). For example, AFM-NMM, by applying some contact mechanics models such as JKR or DMT, etc., has been widely used to quantitatively measure the nanoscale mechanical properties of polymer materials. However, these continuum contact models have many assumptions.²⁸ Depending on the tip shape, contact radius, strength of tip-sample adhesion, and softness of sample, the assumptions of these models are essential to understand to interpret the force-distance curves accurately.^{31,32,330} Recent work has shown that blunt tips must be used to get valid absolute values of mechanical properties.^{30,331} With the continuous development in understandings of the tip-sample interaction and modeling, improvements in

spatial and temporal resolution, multiparametric and multifunctional characterization, advances in AFM should lead to a more comprehensive understanding of the dynamic, structural, mechanical, chemical, and functional heterogeneity of complex polymer systems and allow one to address outstanding questions in polymers in the coming decades.

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Thomas P. Russell, the Silvio O. Conte Distinguished Professor of Polymer Science and Engineering at the University of Massachusetts in Amherst, received his PhD in 1979 from the same institution. He was a Research Associate at the University of Mainz (1979–1981) and a

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